

Sample &

Buy



OPA2333-HT

Reference

Design

SBOS483I-JULY 2009-REVISED MAY 2015

OPA2333-HT 1.8-V Micropower CMOS Operational Amplifier Zero-Drift Series

Technical

Documents

1 Features

- Low Offset Voltage: 26 µV (Maximum)
- 0.01-Hz to 10-Hz Noise: 1.5 μV_{PP}
- Quiescent Current: 50 µA
- Single-Supply Operation
- Supply Voltage: 1.8 V to 5.5 V
- Rail-to-Rail Input and Output
- Supports Extreme Temperature Applications
- Controlled Baseline
- One Assembly/Test Site
- One Fabrication Site
- Available in Extreme (–55°C to 210°C) Temperature Range
- Extended Product Life Cycle
- Extended Product-Change Notification
- Product Traceability
- Texas Instruments' high temperature products use highly optimized silicon (die) solutions with design and process enhancements to maximize performance over extended temperatures.

NOTE: Custom temperature ranges available

2 Applications

- Down-Hole Drilling
- High Temperature Environments

3 Description

Tools &

Software

The OPA2333 series of CMOS operational amplifiers uses a proprietary auto-calibration technique to simultaneously provide very low offset voltage and near-zero drift over time and temperature⁽¹⁾. These miniature, high-precision, low-quiescent-current amplifiers offer high-impedance inputs that have a common-mode range 100 mV beyond the rails, and rail-to-rail output that swings within 150 mV of the rails. Single or dual supplies as low as 1.8 V (±0.9 V) and up to 5.5 V (±2.75 V) may be used. They are optimized for low-voltage single-supply operation.

Support &

Community

2.2

The OPA2333 offers excellent common-mode rejection ratio (CMRR) without the crossover associated with traditional complementary input stages. This design results in superior performance for driving analog-to-digital converters (ADCs) without degradation of differential linearity.

Device Information⁽²⁾

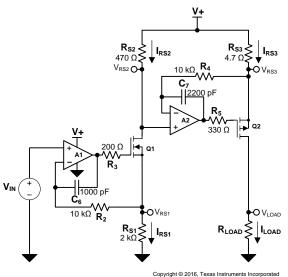
PART NUMBER	PACKAGE	BODY SIZE (NOM)				
	SOIC (8)	4.90 mm × 3.91 mm				
OPA2333-HT	CFP (8)	6.90 mm × 5.65 mm				
UPA2333-01	CFP (8)	7.035 mm × 5.75 mm				
	CDIP SB (8)	18.55 mm × 7.49 mm				

(1) See Electrical Characteristics for

performance degradation over temperature.

(2) For all available packages, see the orderable addendum at the end of the data sheet.

Typical Application



An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.

STRUMENTS www.ti.com

Page

Page

EXAS

Table of Contents

1	Feat	tures 1							
2	Арр	Applications 1							
3	Des	cription1							
4	Rev	ision History 2							
5	Pin	Configuration and Functions							
6	Spe	cifications							
	6.1	Absolute Maximum Ratings 5							
	6.2	ESD Ratings 5							
	6.3	Recommended Operating Conditions 5							
	6.4	Thermal Information 5							
	6.5	Electrical Characteristics							
	6.6	Typical Characteristics							
7	Deta	ailed Description 12							
	7.1	Overview 12							
	7.2	Functional Block Diagrams 12							
	7.3	Feature Description 12							

	7.4	Device Functional Modes	14
8	App	lication and Implementation	15
	8.1	Application Information	15
	8.2	Typical Applications	15
	8.3	System Examples	20
9	Pow	er Supply Recommendations	22
10	Laye	out	23
		Layout Guidelines	
	10.2	Layout Example	23
11	Dev	ice and Documentation Support	24
	11.1	Device Support	24
	11.2	Community Resources	24
	11.3	Trademarks	24
	11.4	Electrostatic Discharge Caution	24
	11.5	Glossary	24
12		hanical, Packaging, and Orderable	
	Infor	mation	<mark>24</mark>

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision H (November 2013) to Revision I

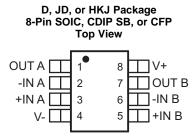
•	Added Pin Configuration and Functions section, ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section	1
•	Removed Ordering Information table	1
•	Moved temperature range from <i>Electrical Characteristics</i> table to the <i>Absolute Maximum Ratings</i> and <i>Recommended Operating Conditions</i> tables	5
		_

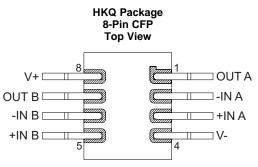
Changes from Revision G (September 2012) to Revision H

•	Changed Operating Life Derating Chart	8



5 Pin Configuration and Functions





HKQ as formed or HKL mounted dead bug

Pin Functions

PIN		1/0	DESCRIPTION			
NO.	NAME	I/O	DESCRIPTION			
1	OUT A	0	Analog output channel A			
2	–IN A	I	Inverting analog input channel A			
3	+IN A	I	ninverting analog input channel A			
5	+IN B	I	ninverting analog input channel B			
6	–IN B	I	verting analog input channel B			
4	V–	—	Negative (lowest) power supply			
7	OUT B	0	nalog output channel B			
8	V+	—	sitive (highest) power supply			



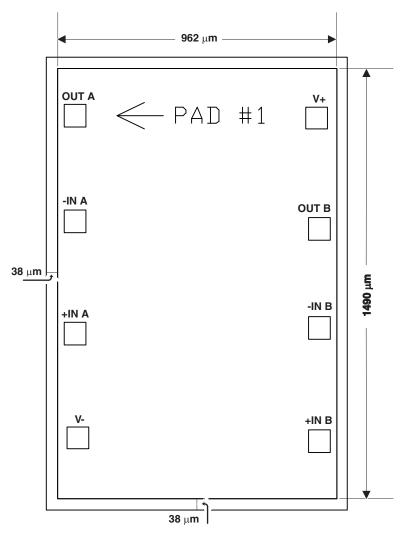


Table 1. Bare Die Information

DIE THICKNESS BACKSIDE FINISH		BACKSIDE POTENTIAL	BOND PAD METALLIZATION COMPOSITION		
15 mils.	Silicon with backgrind	V-	Al-Si-Cu (0.5%)		

Table 2. Bond Pad Coordinates

DESCRIPTION	PAD NUMBER	Α	В	С	D
OUT A	1	21.20	1288.50	97.20	1364.50
–IN A	2	21.20	923.65	97.20	999.65
+IN A	3	21.20	533.05	97.20	609.05
V–	4	31.30	172.20	107.30	248.20
+IN B	5	864.80	162.25	940.80	238.25
–IN B	6	864.80	552.65	940.80	628.65
OUT B	7	864.80	897.10	940.80	973.10
V+	8	854.70	1280.45	930.70	1356.45



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT	
Supply voltage	Supply voltage		7	V	
Signal input terminals, voltage ⁽²⁾		-0.3	(V+) + 0.3	V	
Output short circuit ⁽³⁾		Con	Continuous		
	JD, HKJ, HKQ packages	-55	210	*0	
Operating temperature	D package	-55	175	°C	
	JD, HKJ, HKQ packages		210		
Junction temperature	D package		175	- °C	
Storage temperature, T _{stg}		-65	210	°C	

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) Input terminals are diode clamped to the power-supply rails. Input signals that can swing more than 0.3 V beyond the supply rails should be current limited to 10 mA or less.

(3) Short circuit to ground, one amplifier per package.

6.2 ESD Ratings

			VALUE	UNIT
V	Electrostatic	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±4000	V
V _(ESD))) discharge	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT	
Supply voltage, $V_S = (V+) - (V-)$		1.8 (±0.9)	5 (±2.5)	5.5 (±2.75)	V	
Operating temperature	JD, HKJ, HKQ packages	-55		210	ŝ	
Operating temperature	D package	-55		175	°С	

6.4 Thermal Information

				OPA2333-HT			
	THERMAL M	JD (CDIP SB)	HKJ (CFP)	HKQ (CFP)	D (SOIC)	UNIT	
		8 PINS	8 PINS	8 PINS	8 PINS		
R _{θJA}	Junction-to-ambient thermal	High-K board ⁽³⁾ , no airflow	—	—	_	117.5	°C/W
	resistance ⁽²⁾	No airflow	—	—	—	—	
	Junction-to-case (top) thermal resistance		53.8	57.7		62.0	°C/W
$R_{\theta JC(top)}$		to ceramic side of case	—	—	15.2	-	
		to top of case lid (metal side of case)	—	—	_	—	
$R_{\theta J B}$	Junction-to-board thermal resistance	High-K board without underfill	76.0	61.0	151.6	57.7	°C/W
Ψ_{JT}	Junction-to-top characterization parameter			—	—	19.4	°C/W
ψ_{JB}	J _{JB} Junction-to-board characterization parameter		—	—	—	57.2	°C/W
R _{0JC(bot)}				15.2	56.9	_	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

(2) The intent of R_{0JA} specification is solely for a thermal performance comparison of one package to another in a standardized environment.

This methodology is not meant to and will not predict the performance of a package in an application-specific environment.

(3) JED51-7, high effective thermal conductivity test board for leaded surface mount packages

Copyright © 2009–2015, Texas Instruments Incorporated

OPA2333-HT

SBOS483I-JULY 2009-REVISED MAY 2015

www.ti.com

ISTRUMENTS

EXAS

6.5 Electrical Characteristics

 V_{S} = 1.8 V to 5.5 V, T_{A} = 25°C, R_{L} = 10 k Ω connected to $V_{S}/2$, V_{CM} = $V_{S}/2$, and V_{OUT} = $V_{S}/2$ (unless otherwise noted).

		DITIONS		TYP	MAX	UNIT			
/OLTAGE									
		T _A = 25°C		2	10				
1 · · · · · ·		$T_A = -55^{\circ}C$ to $125^{\circ}C$			22	μV			
Input offset voltage	$V_{\rm S} = 5 V$	$T_A = -55^{\circ}C$ to $175^{\circ}C^{(1)}$			26				
		$T_A = -55^{\circ}C$ to $210^{\circ}C^{(2)}$			26	μV			
		$T_A = -55^{\circ}C$ to $125^{\circ}C$		0.02					
Input Offset Voltage	V _S = 5 V	$T_A = -55^{\circ}C$ to $175^{\circ}C^{(1)}$		0.05		µV/°C			
		$T_A = -55^{\circ}C$ to $210^{\circ}C^{(2)}$		0.05					
		$T_A = -55^{\circ}C$ to $125^{\circ}C$		1	6				
	V _S = 1.8 V to 5.5 V	$T_A = -55^{\circ}C$ to $175^{\circ}C^{(1)}$		1.2	8	μV/V			
		$T_A = -55^{\circ}C$ to $210^{\circ}C^{(2)}$		1.7	11				
AS CURRENT									
	T _A = 25°C			±70	±200				
	$T_A = -55^{\circ}C$ to $125^{\circ}C$			±150					
Input bias current	$T_{A} = -55^{\circ}C$ to 175°C			±1250		рA			
	$T_{A} = -55^{\circ}C \text{ to } 210^{\circ}C$			±5300					
				±140	±400	рА			
Input offset current	$T_{A} = -55^{\circ}C \text{ to } 175^{\circ}C$			±700					
I _{OS} Input offset current	$T_{A} = -55^{\circ}C$ to 210°C			±10600					
		$T_A = -55^{\circ}C$ to $125^{\circ}C$		0.3		μV _{ΡΡ}			
	f = 0.01 Hz to 1 Hz			1					
Input Noise Voltage				1					
				1.1					
	f = 0.1 Hz to 10 Hz								
Input Noise Current Density	f = 10 Hz					fA/√H			
		~							
	$T_{\Lambda} = -55^{\circ}C$ to $125^{\circ}C$		(V–) – 0.1		(V+) + 0.1				
Common mode voltage						v			
range									
Common-Mode Rejection Ratio		$T_{A} = -55^{\circ}C$ to 125°C		130	()				
	$(V-) - 0.1 V < V_{CM} < (V+) +$					dB			
	0.1 V								
PACITANCE		1 _A 00 0 10 210 0		0.					
	$T_{1} = -55^{\circ}C$ to 125°C			2					
Differential						pF			
						- pr			
Common mode									
	~					pF			
	TA = 00 0 10 210 0			12.20					
		T55°C to 125°C	104	120					
Open-loop voltage gain	(V–) + 100 mV < V _O < (V+) –	$T_A = -55^{\circ}C \text{ to } 125^{\circ}C$ $T_A = -55^{\circ}C \text{ to } 175^{\circ}C^{(1)}$	93	130		dB			
	$100 \text{ mV}, \text{R}_{\text{L}} = 10 \text{ k}\Omega$	$I_A = -35 \cup 10 175 \cup 17$	93	110		uВ			
	Input offset voltage Input Offset Voltage Temperature Drift Input Offset Voltage vs Power Supply AS CURRENT Input bias current Input offset current Input Noise Voltage Input Noise Voltage Common mode voltage range Common-Mode Rejection Ratio PACITANCE Differential Common mode	Input offset voltage Temperature Drift $V_S = 5 \vee$ Input Offset Voltage Power Supply $V_S = 5 \vee$ Input Offset Voltage vs Power Supply $V_S = 1.8 \vee to 5.5 \vee$ AS CURRENT $T_A = 25^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ Input bias current $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ Input offset current $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ Input Noise Voltage $f = 0.01 \text{ Hz to 1 Hz}$ Input Noise Voltage $f = 0.1 \text{ Hz to 10 Hz}$ Input Noise Current Density $f = 10 \text{ Hz}$ VLTAGE RANGE (3) $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ Common mode voltage range $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55^{\circ}C to 125^{\circ}C$ Differential $T_A = -55^{\circ}C to 125^{\circ}C$ $T_A = -55$	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$			

(1) Minimum and maximum parameters are characterized for operation at $T_A = 175^{\circ}C$, but may not be production tested at that temperature. Production test limits with statistical quardhands are used to ensure high temperature performance.

(1) Immunant and maximum parameters are characterized for operation at T_A = 110 C, but may not be production tested at that
 (2) Minimum and maximum parameters are characterized for operation at T_A = 210°C, but may not be production tested at that

temperature. Production test limits with statistical guardbands are used to ensure high temperature performance.

(3) The OPA2333-HT is not intended to be used as a comparator due to its limited differential input range capability.

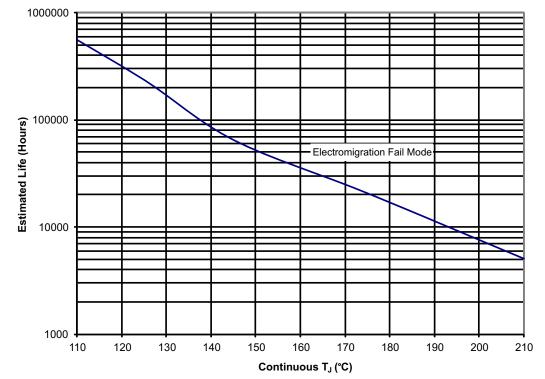


Electrical Characteristics (continued)

 $V_{S} = 1.8 \text{ V to 5.5 V}, \text{ } T_{A} = 25^{\circ}\text{C}, \text{ } R_{L} = 10 \text{ } k\Omega \text{ connected to } V_{S}/2, \text{ } V_{CM} = V_{S}/2, \text{ and } V_{OUT} = V_{S}/2 \text{ (unless otherwise noted)}.$

	PARAMETER	TEST C	ONDITIONS	MIN	TYP	MAX	UNIT	
FREQUE	ENCY RESPONSE						-	
			$T_A = -55^{\circ}C$ to $125^{\circ}C$		350			
GBW Gain-bandwidth product	Gain-bandwidth product	C _L = 100 pF	$T_A = -55^{\circ}C$ to 175°C		350		kHz	
		$T_A = -55^{\circ}C$ to 210°C		350				
SR Slew rate			$T_A = -55^{\circ}C$ to $125^{\circ}C$		0.16			
	G = 1	$T_A = -55^{\circ}C$ to 175°C	0.25			V/µs		
		$T_A = -55^{\circ}C$ to 210°C						
OUTPUT	г							
	Voltage output swing from		T _A = 25°C		30	50		
		D 40.60	$T_A = -55^{\circ}C$ to $125^{\circ}C$			85		
rail	$R_L = 10 \ k\Omega$	$T_A = -55^{\circ}C \text{ to } 175^{\circ}C^{(1)}$			110	mV		
			$T_A = -55^{\circ}C \text{ to } 210^{\circ}C^{(2)}$			150		
ISC	Short-circuit current	$T_A = 25^{\circ}C$			±5		mA	
	Open-loop output impedance ⁽⁴⁾	f = 350 kHz, I _O = 0			2		kΩ	
POWER	SUPPLY							
Vs	Specified voltage range	$T_A = -55^{\circ}C \text{ to } 210^{\circ}C^{(2)}$		1.8		5.5	V	
			T _A = 25°C		17	25		
	Quiescent current per		$T_A = -55^{\circ}C$ to $125^{\circ}C$			30	μA)	
	amplifier	I _O = 0	$T_A = -55^{\circ}C \text{ to } 175^{\circ}C^{(1)}$		35	40		
			$T_A = -55^{\circ}C \text{ to } 210^{\circ}C^{(2)}$		50	80		
	Turnon time	V _S = 5 V	T _A = 25°C		100		μs	

(4) See Typical Characteristics.



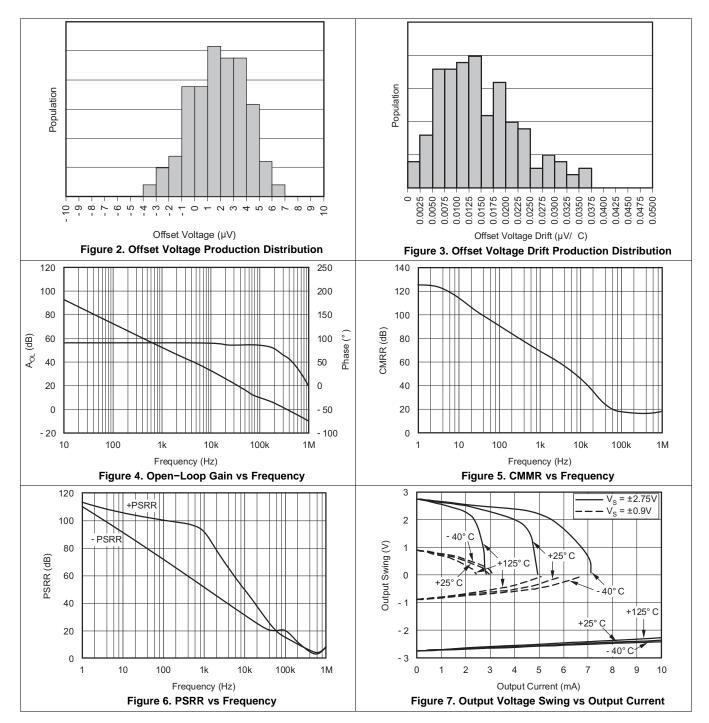
- (1) See datasheet for absolute maximum and minimum recommended operating conditions.
- (2) Silicon operating life design goal is 10 years at 105°C junction temperature (does not include package interconnect life).
- (3) The predicted operating lifetime vs. junction temperature is based on reliability modeling using electromigration as the dominant failure mechanism affecting device wearout for the specific device process and design characteristics.
- (4) This device is qualified for 1000 hours of continuous operation at maximum rated temperature.

Figure 1. OPA2333SKGD1 and OPA2333HD Operating Life Derating Chart



6.6 Typical Characteristics

At $T_A = 25^{\circ}C$, $V_S = 5$ V, and $C_L = 0$ pF (unless otherwise noted).

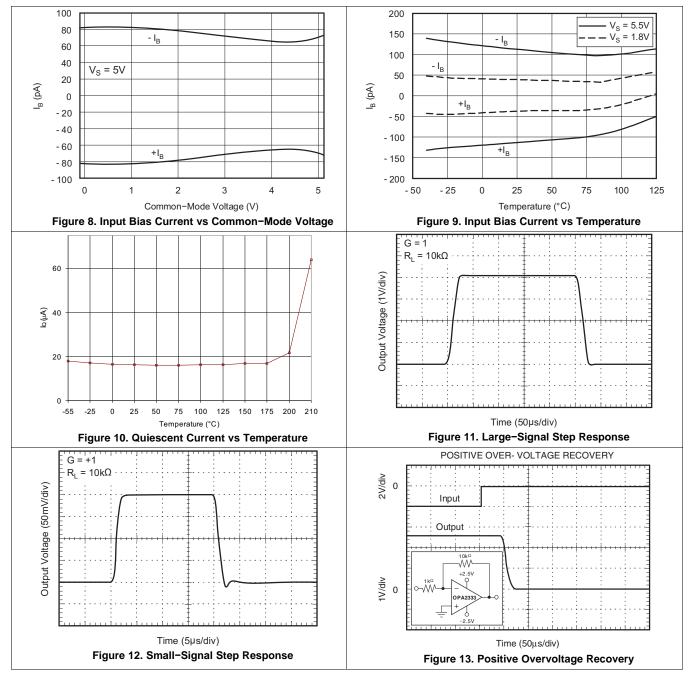


OPA2333-HT SBOS483I – JULY 2009–REVISED MAY 2015



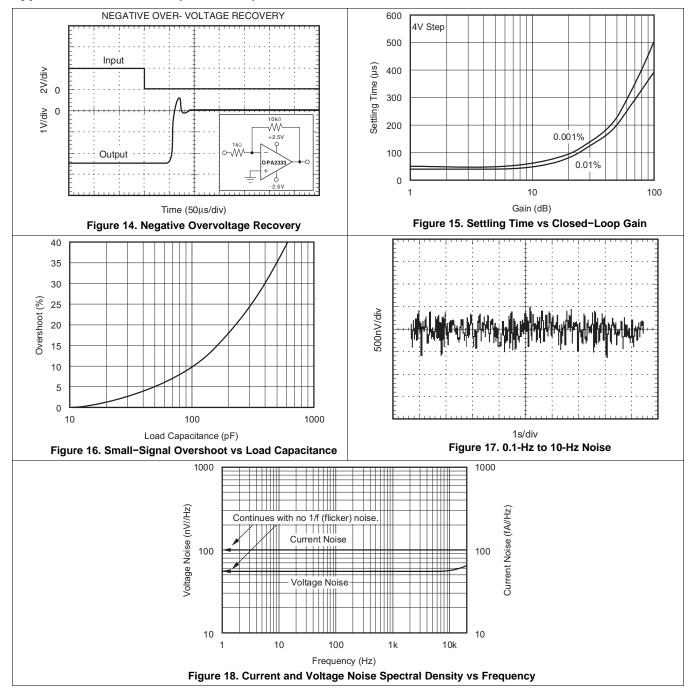
www.ti.com

Typical Characteristics (continued)





Typical Characteristics (continued)





7 Detailed Description

7.1 Overview

The OPA2333 is a Zero-Drift, low-power, rail-to-rail input and output dual operational amplifier. The device operates from 1.8 V to 5.5 V, is unity-gain stable, and is suitable for a wide range of general-purpose applications. The Zero-Drift architecture provides low offset voltage and near zero offset voltage drift.

7.2 Functional Block Diagrams

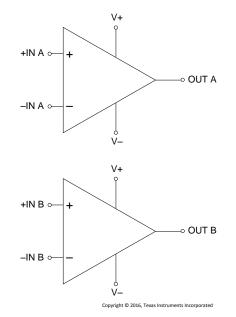


Figure 19. Functional Block Diagram for A and B Amps

7.3 Feature Description

The OPA2333 is unity-gain stable and free from unexpected output phase reversal. It uses a proprietary autocalibration technique to provide low offset voltage and very low drift over time and temperature. For lowest offset voltage and precision performance, circuit layout and mechanical conditions should be optimized. Avoid temperature gradients that create thermoelectric (Seebeck) effects in the thermocouple junctions formed from connecting dissimilar conductors. These thermally-generated potentials can be made to cancel by ensuring they are equal on both input terminals. Other layout and design considerations include: ⁽⁵⁾

- Use low thermoelectric-coefficient conditions (avoid dissimilar metals)
- Thermally isolate components from power supplies or other heat sources
- · Shield operational amplifier and input circuitry from air currents, such as cooling fans

Following these guidelines will reduce the likelihood of junctions being at different temperatures, which can cause thermoelectric voltages of 0.1 μ V/°C or higher, depending on materials used.

7.3.1 Operating Voltage

The OPA2333 operational amplifier operates over a power-supply range of 1.8 V to 5.5 V (\pm 0.9 V to \pm 2.75 V). Supply voltages higher than 7 V (absolute maximum) can permanently damage the device. Parameters that vary over supply voltage or temperature are shown in *Typical Characteristics*.

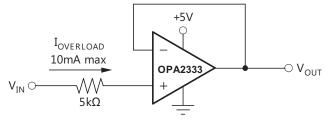


Feature Description (continued)

7.3.2 Input Voltage

The OPA2333 input common-mode voltage range extends 0.1 V beyond the supply rails. The OPA2333 is designed to cover the full range without the troublesome transition region found in some other rail-to-rail amplifiers.

Normally, input bias current is about 70 pA; however, input voltages exceeding the power supplies can cause excessive current to flow into or out of the input pins. Momentary voltages greater than the power supply can be tolerated if the input current is limited to 10 mA. This limitation is easily accomplished with an input resistor (see Figure 20).



Copyright © 2016, Texas Instruments Incorporated

Current-limiting resistor required if input voltage exceeds supply rails by ≥ 0.5 V

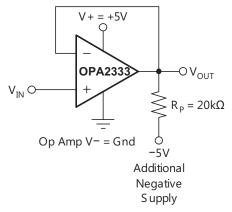
Figure 20. Input Current Protection

7.3.3 Internal Offset Correction

The OPA2333 operational amplifier uses an auto-calibration technique with a time-continuous 350-kHz operational amplifier in the signal path. This amplifier is zero corrected every 8 μ s using a proprietary technique. Upon power up, the amplifier requires approximately 100 μ s to achieve specified V_{OS} accuracy. This design has no aliasing or flicker noise.

7.3.4 Achieving Output Swing to the Operational Amplifier Negative Rail

Some applications require output voltage swings from 0 V to a positive full-scale voltage (such as 2.5 V) with excellent accuracy. With most single-supply operational amplifiers, problems arise when the output signal approaches 0 V, near the lower output swing limit of a single-supply operational amplifier. A good single-supply operational amplifier may swing close to single-supply ground, but will not reach ground. The output of the OPA2333 can be made to swing to ground, or slightly below, on a single-supply power source. To do so requires the use of another resistor and an additional, more negative, power supply than the operational amplifier negative supply. A pulldown resistor may be connected between the output and the additional negative supply to pull the output down below the value that the output would otherwise achieve (see Figure 21).



Copyright © 2016, Texas Instruments Incorporated

Figure 21.	V _{OUT} Range to Ground	
------------	----------------------------------	--

OPA2333-HT SBOS483I – JULY 2009–REVISED MAY 2015



Feature Description (continued)

The OPA2333 has an output stage that allows the output voltage to be pulled to its negative supply rail, or slightly below, using the technique previously described. This technique only works with some types of output stages. The OPA2333 has been characterized to perform with this technique; however, the recommended resistor value is approximately 20 k Ω .

NOTE

This configuration will increase the current consumption by several hundreds of microamps.

Accuracy is excellent down to 0 V and as low as -2 mV. Limiting and nonlinearity occurs below -2 mV, but excellent accuracy returns as the output is again driven above -2 mV. Lowering the resistance of the pulldown resistor allows the operational amplifier to swing even further below the negative rail. Resistances as low as 10 k Ω can be used to achieve excellent accuracy down to -10 mV.

7.4 Device Functional Modes

The OPA2333 device has a single functional mode. The device is powered on as long as the power supply voltage is between 1.8 V (\pm 0.9 V) and 5.5 V (\pm 2.75 V).



8 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

8.1 Application Information

The OPA2333 family is a unity-gain stable, precision operational amplifier with very low offset voltage drift; these devices are also free from output phase reversal. Applications with noisy or high-impedance power supplies require decoupling capacitors close to the device power-supply pins. In most cases, 0.1-µF capacitors are adequate.

8.2 Typical Applications

8.2.1 High-Side Voltage-to-Current (V-I) Converter

The circuit shown in Figure 22 is a high-side voltage-to-current (V-I) converter. It translates in input voltage of 0 V to 2 V to and output current of 0 mA to 100 mA. Figure 23 shows the measured transfer function for this circuit. The low offset voltage and offset drift of the OPA2333 facilitate excellent dc accuracy for the circuit.

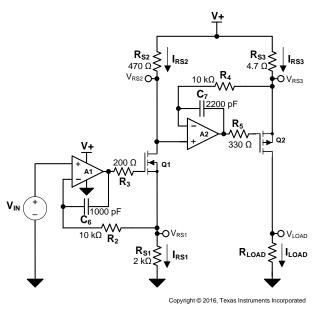


Figure 22. High-Side Voltage-to-Current (V-I) Converter



Typical Applications (continued)

8.2.1.1 Design Requirements

The design requirements are as follows:

- Supply Voltage: 5-V DC
- Input: 0-V to 2-V DC
- Output: 0-mA to 10-mA DC

8.2.1.2 Detailed Design Procedure

The V-I transfer function of the circuit is based on the relationship between the input voltage, V_{IN} , and the three current sensing resistors, R_{S1} , R_{S2} , and R_{S3} . The relationship between V_{IN} and R_{S1} determines the current that flows through the first stage of the design. The current gain from the first stage to the second stage is based on the relationship between R_{S2} and R_{S3} .

For a successful design, pay close attention to the DC characteristics of the operational amplifier chosen for the application. To meet the performance goals, this application benefits from an operational amplifier with low offset voltage, low temperature drift, and rail-to-rail output. The OPA2333 CMOS operational amplifier is a high-precision, $5-\mu$ V offset, $0.05-\mu$ V/°C drift amplifier optimized for low-voltage, single-supply operation with an output swing to within 50 mV of the positive rail. The OPA2333 family uses chopping techniques to provide low initial offset voltage and near-zero drift over time and temperature. Low offset voltage and low drift reduce the offset error in the system, making these devices appropriate for precise DC control. The rail-to-rail output stage of the OPA2333 ensures that the output swing of the operational amplifier is able to fully control the gate of the MOSFET devices within the supply rails.

See TIPD102 for a detailed error analysis, design procedure, and additional measured results.

8.2.1.3 Application Curve

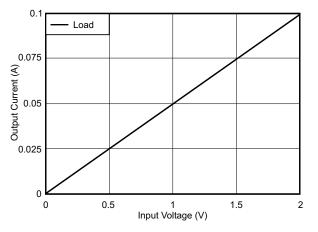


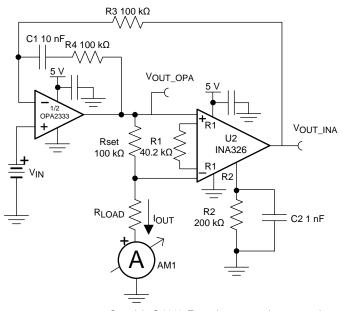
Figure 23. Measured Transfer Function for High-Side V-I Converter



Typical Applications (continued)

8.2.2 Precision, Low-Level Voltage-to-Current (V-I) Converter

The circuit shown in Figure 24 is a precision, low-level voltage-to-current (V-I) converter. The converter translates in input voltage of 0 V to 5 V and output current of 0 μ A to 5 μ A. Figure 25 shows the measured transfer function for this circuit. The low offset voltage and offset drift of the OPA2333 facilitate excellent dc accuracy for the circuit. Figure 26 shows the calibrated error for the entire range of the circuit.



Copyright © 2016, Texas Instruments Incorporated

Figure 24. Low-Level, Precision V-I Converter

8.2.2.1 Design Requirements

The design requirements are as follows:

- Supply Voltage: 5-V DC
- Input: 0-V to 5-V DC
- Output: 0-µA to 5-µA DC

8.2.2.2 Detailed Design Procedure

The V-I transfer function of the circuit is based on the relationship between the input voltage, V_{IN} , R_{SET} , and the instrumentation amplifier (INA) gain. During operation, the input voltage divided by the INA gain appears across the set resistor in Equation 1:

$$V_{SET} = V_{IN}/G_{INA}$$

(1)

The current through R_{SET} must flow through the load, so I_{OUT} is V_{SET} / R_{SET} . I_{OUT} remains a well-regulated current as long as the total voltage across R_{SET} and R_{LOAD} does not violate the output limits of the operational amplifier or the input common-mode limits of the INA. The voltage across the set resistor (V_{SET}) is the input voltage divided by the INA gain (that is, $V_{SET} = 1 \text{ V} / 10 = 0.1 \text{ V}$). The current is determined by V_{SET} and R_{SET} shown in Equation 2:

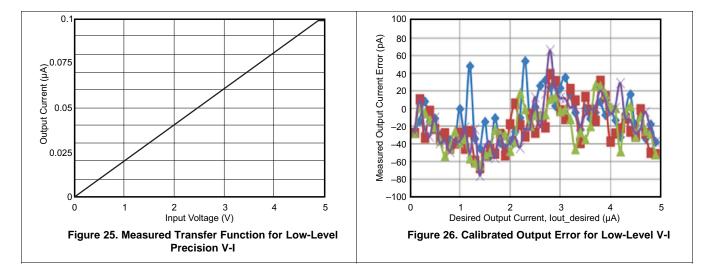
$$I_{OUT} = V_{SET} / R_{SET} = 0.1 \text{ V} / 100 \text{ k}\Omega = 1 \text{ }\mu\text{A}$$

(2)

See TIPD107 for a detailed error analysis, design procedure, and additional measured results.

Typical Applications (continued)

8.2.2.3 Application Curves



8.2.3 Composite Amplifier

The circuit shown in Figure 27 is a composite amplifier used to drive the reference on the ADS8881. The OPA2333 provides excellent dc accuracy, and the THS4281 allows the output of the circuit to respond quickly to the transient current requirements of a typical SAR data converter reference input. The ADS8881 system was optimized for THD and achieved a measured performance of –110 dB. The linearity of the ADC is shown Figure 28.

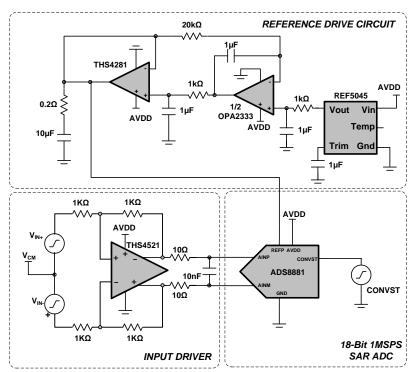


Figure 27. Composite Amplifier Reference Driver Circuit



Typical Applications (continued)

8.2.3.1 Design Requirements

The design requirements for this block design are:

- System Supply Voltage: 5-V DC
- ADC Supply Voltage: 3.3-V DC
- ADC Sampling Rate: 1 MSPS
- ADC Reference Voltage (VREF): 4.5-V DC
- ADC Input Signal: A differential input signal with amplitude of V_{pk} = 4.315 V (-0.4 dBFS to avoid clipping) and frequency, f_{IN} = 10 kHz are applied to each differential input of the ADC

8.2.3.2 Detailed Design Procedure

The two primary design considerations to maximize the performance of a high-resolution SAR ADC are the input driver and the reference driver design. The circuit comprises the critical analog circuit blocks, the input driver, anti-aliasing filter, and the reference driver. Each analog circuit block should be carefully designed based on the ADC performance specifications in order to maximize the distortion and noise performance of the data acquisition system while consuming low power. The diagram includes the most important specifications for each individual analog block. This design systematically approaches the design of each analog circuit block to achieve a 16-bit, low-noise and low-distortion data acquisition system for a 10-kHz sinusoidal input signal. The first step in the design requires an understanding of the requirement of extremely low distortion input driver amplifier. This understanding helps in the decision of an appropriate input driver configuration and selection of an input amplifier to meet the system requirements. The next important step is the design of the anti-aliasing RC-filter to attenuate ADC kick-back noise while maintaining the amplifier stability. The final design challenge is to design a high-precision reference driver circuit, which would provide the required value VREF with low offset, drift, and noise contributions.

In designing a very low distortion data acquisition block, it is important to understand the sources of nonlinearity. Both the ADC and the input driver introduce nonlinearity in a data acquisition block. To achieve the lowest distortion, the input driver for a high-performance SAR ADC must have a distortion that is negligible against the ADC distortion. This parameter requires the input driver distortion to be 10 dB lower than the ADC THD. This stringent requirement ensures that overall THD of the system is not degraded by more than –0.5 dB.

$$\text{THD}_{\text{AMP}} < \text{THD}_{\text{ADC}} - 10 \text{ dB}$$

(3)

It is therefore important to choose an amplifier that meets the above criteria to avoid the system THD from being limited by the input driver. The amplifier nonlinearity in a feedback system depends on the available loop gain. See TIPD115 for a detailed error analysis, design procedure, and additional measured results.

8.2.3.3 Application Curve

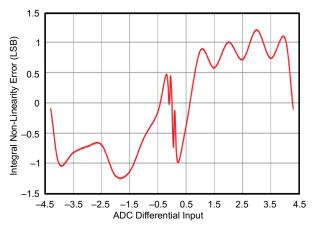


Figure 28. Linearity of the ADC8881 System

8.3 System Examples

8.3.1 Temperature Measurement Application

Figure 29 shows a temperature measurement application.

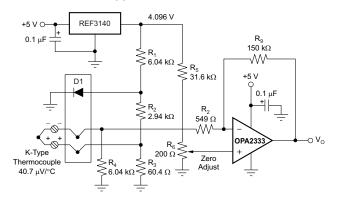


Figure 29. Temperature Measurementf

8.3.2 Single Operational Amplifier Bridge Amplifier Application

Figure 30 shows the basic configuration for a bridge amplifier.

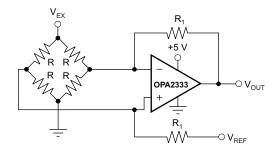
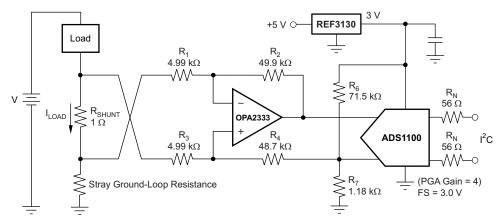


Figure 30. Single Operational Amplifier Bridge Amplifier

8.3.3 Low-Side Current Monitor Application

A low-side current shunt monitor is shown in Figure 31. R_N are operational resistors used to isolate the ADS1100 from the noise of the digital I²C bus. The ADS1100 is a 16-bit converter; therefore, a precise reference is essential for maximum accuracy. If absolute accuracy is not required and the 5-V power supply is sufficiently stable, the REF3130 can be omitted.



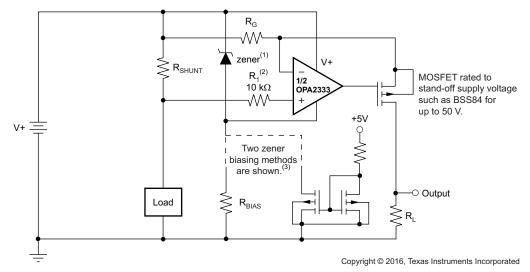
NOTE: 1% resistors provide adequate common-mode rejection at small ground-loop errors.

Figure 31. Low-Side Current Monitor



8.3.4 Other Applications

Additional application ideas are shown in Figure 32 through Figure 35.



- (1) Zener rated for operational amplifier supply capability (that is, 5.1 V for OPA2333).
- (2) Current-limiting resistor.
- (3) Choose zener biasing resistor or dual N-MOSFETs (FDG6301N, NTJD4001N, or Si1034).

Figure 32. High-Side Current Monitor

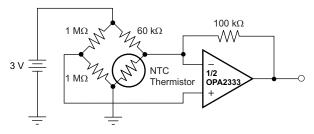


Figure 33. Thermistor Measurement

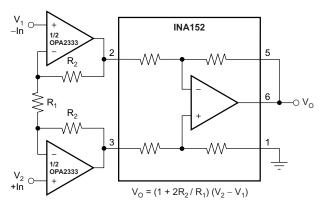
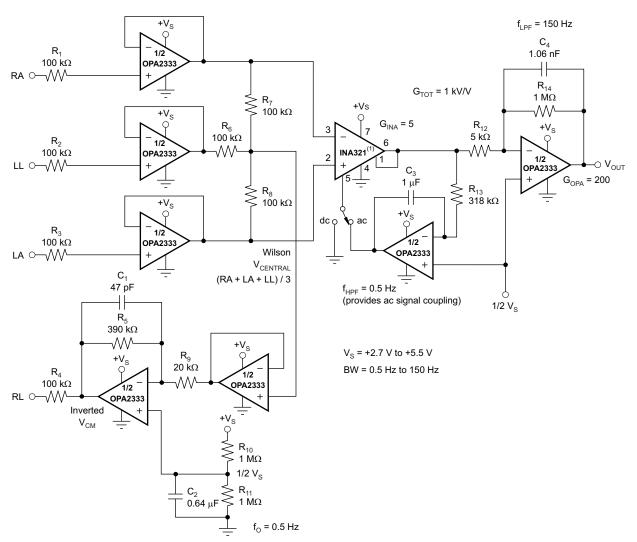


Figure 34. Precision Instrumentation Amplifier

Texas Instruments

www.ti.com



(1) Other instrumentation amplifiers can be used, such as the INA326, which has lower noise, but higher quiescent current.

Figure 35. Single-Supply, Very Low Power, ECG Circuit

9 Power Supply Recommendations

The OPA2333 is specified for operation from 1.8 V to 5.5 V (± 0.9 V to ± 2.75 V); many specifications apply from -40° C to 125°C. The *Recommended Operating Conditions* presents parameters that can exhibit significant variance with regard to operating voltage or temperature.

CAUTION

Supply voltages larger than 7 V can permanently damage the device (see the *Absolute Maximum Ratings*).

TI recommends placing 0.1-µF bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see *Layout*.



10 Layout

10.1 Layout Guidelines

10.1.1 General Layout Guidelines

Pay attention to good layout practices. Keep traces short and when possible, use a printed-circuit board (PCB) ground plane with surface-mount components placed as close to the device pins as possible. Place a $0.1-\mu$ F capacitor closely across the supply pins. Apply these guidelines throughout the analog circuit to improve performance and provide benefits, such as reducing the electromagnetic interference (EMI) susceptibility.

Operational amplifiers vary in susceptibility to radio frequency interference (RFI). RFI can generally be identified as a variation in offset voltage or DC signal levels with changes in the interfering RF signal. The OPA2333 is specifically designed to minimize susceptibility to RFI and demonstrates remarkably low sensitivity compared to previous generation devices. Strong RF fields may still cause varying offset levels.

10.1.2 DFN Layout Guidelines

Solder the exposed leadframe die pad on the DFN package to a thermal pad on the PCB. A mechanical drawing showing an example layout is attached at the end of this data sheet. Refinements to this layout may be necessary based on assembly process requirements. Mechanical drawings located at the end of this data sheet list the physical dimensions for the package and pad. The five holes in the landing pattern are optional, and are intended for use with thermal vias that connect the leadframe die pad to the heatsink area on the PCB.

Soldering the exposed pad significantly improves board-level reliability during temperature cycling, key push, package shear, and similar board-level tests. Even with applications that have low-power dissipation, the exposed pad must be soldered to the PCB to provide structural integrity and long-term reliability.

10.2 Layout Example

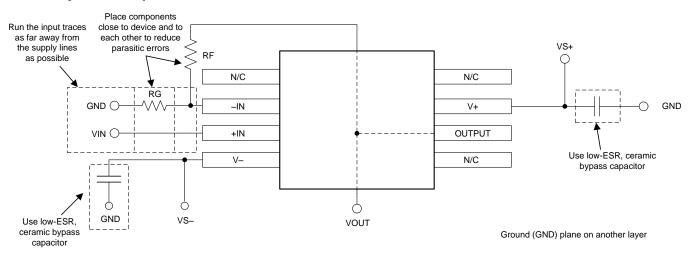


Figure 36. OPA2333-HT Layout Example

TEXAS INSTRUMENTS

www.ti.com

11 Device and Documentation Support

11.1 Device Support

11.1.1 Development Support

For development support on this product, see the following:

- High-Side V-I Converter, 0 V to 2 V to 0 mA to 100 mA, 1% Full-Scale Error, TIPD102
- Low-Level V-to-I Converter Reference Design, 0-V to 5-V Input to 0-µA to 5-µA Output, TIPD107
- 18-Bit, 1-MSPS, Serial Interface, microPower, Truly-Differential Input, SAR ADC, ADS8881
- Very Low-Power, High-Speed, Rail-To-Rail Input/Output, Voltage Feedback Operational Amplifier, THS4281
- Data Acquisition Optimized for Lowest Distortion, Lowest Noise, 18-bit, 1-MSPS Reference Design, TIPD115
- Self-Calibrating, 16-Bit Analog-to-Digital Converter, ADS1100
- 20-ppm/Degrees C Max, 100-μA, SOT23-3 Series Voltage Reference, REF3130
- Precision, Low Drift, CMOS Instrumentation Amplifier, INA326, INA326

11.2 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E[™] Online Community *TI's Engineer-to-Engineer (E2E) Community.* Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

11.3 Trademarks

E2E is a trademark of Texas Instruments. All other trademarks are the property of their respective owners.

11.4 Electrostatic Discharge Caution



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

11.5 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable Device	Status	Package Type	•	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
OPA2333HD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-4-260C-72 HR	-55 to 175	O2333H	Samples
OPA2333SHKJ	ACTIVE	CFP	HKJ	8	1	TBD	Call TI	N / A for Pkg Type	-55 to 210	OPA2333S HKJ	Samples
OPA2333SHKQ	ACTIVE	CFP	HKQ	8	1	TBD	AU	N / A for Pkg Type	-55 to 210	OPA2333S HKQ	Samples
OPA2333SJD	ACTIVE	CDIP SB	JD	8	1	TBD	POST-PLATE	N / A for Pkg Type	-55 to 210	OPA2333SJD	Samples
OPA2333SKGD1	ACTIVE	XCEPT	KGD	0	100	TBD	Call TI	N / A for Pkg Type	-55 to 210		Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.



29-Jul-2017

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF OPA2333-HT :

- Catalog: OPA2333
- Automotive: OPA2333-Q1

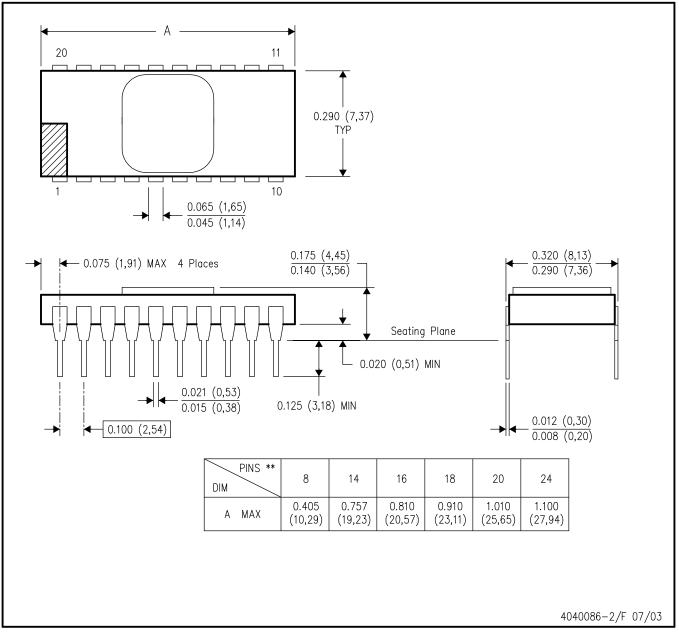
NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects

JD (R-CDIP-T**)

CERAMIC SIDE-BRAZE DUAL-IN-LINE PACKAGE

20 PINS SHOWN



- NOTES: A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. This package is hermetically sealed with a metal lid.
 - D. The terminals are gold plated.
 - E. Falls within MIL STD 1835 CDIP2 T8, T14, T16, T18, T20 and T24 respectively.



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.





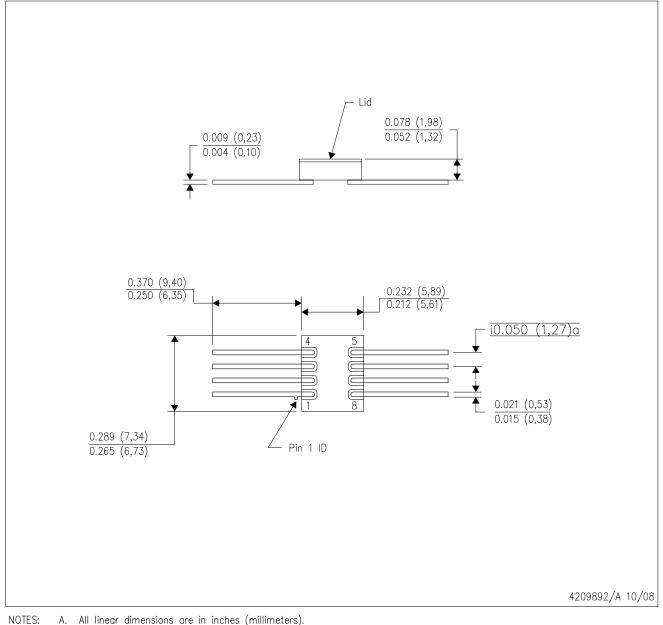
NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



HKJ (R-CDFP-F8)

CERAMIC DUAL FLATPACK

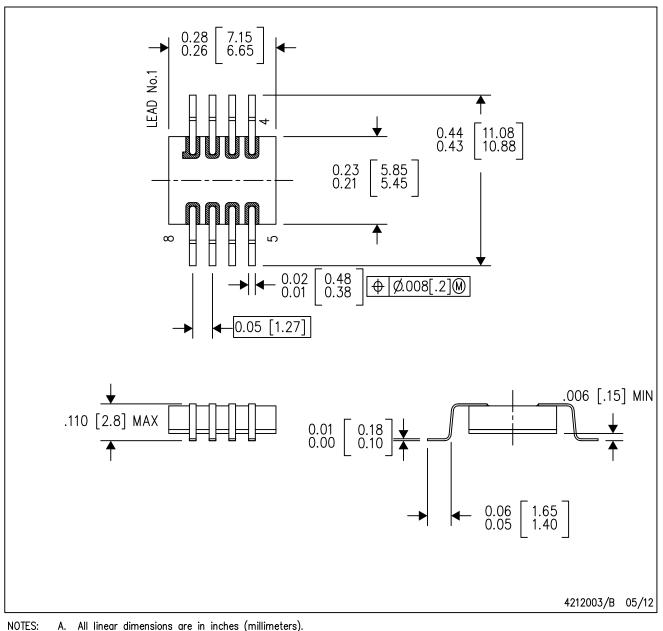


- All linear dimensions are in inches (millimeters).
 - В. This drawing is subject to change without notice.
 - C. This package can be hermetically sealed with a metal lid. D. The terminals will be gold plated.



HKQ (R-CDFP-G8)

CERAMIC GULL WING



- A. All linear dimensions are in inches (millimeters). This drawing is subject to change without notice.
 - Β. C. This package can be hermetically sealed with a metal lid.

 - D. The terminals will be gold plated.E. Lid is not connected to any lead.



IMPORTANT NOTICE

Texas Instruments Incorporated (TI) reserves the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete.

TI's published terms of sale for semiconductor products (http://www.ti.com/sc/docs/stdterms.htm) apply to the sale of packaged integrated circuit products that TI has qualified and released to market. Additional terms may apply to the use or sale of other types of TI products and services.

Reproduction of significant portions of TI information in TI data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such reproduced documentation. Information of third parties may be subject to additional restrictions. Resale of TI products or services with statements different from or beyond the parameters stated by TI for that product or service voids all express and any implied warranties for the associated TI product or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyers and others who are developing systems that incorporate TI products (collectively, "Designers") understand and agree that Designers remain responsible for using their independent analysis, evaluation and judgment in designing their applications and that Designers have full and exclusive responsibility to assure the safety of Designers' applications and compliance of their applications (and of all TI products used in or for Designers' applications) with all applicable regulations, laws and other applicable requirements. Designer represents that, with respect to their applications, Designer has all the necessary expertise to create and implement safeguards that (1) anticipate dangerous consequences of failures, (2) monitor failures and their consequences, and (3) lessen the likelihood of failures that might cause harm and take appropriate actions. Designer agrees that prior to using or distributing any applications that include TI products, Designer will thoroughly test such applications and the functionality of such TI products as used in such applications.

TI's provision of technical, application or other design advice, quality characterization, reliability data or other services or information, including, but not limited to, reference designs and materials relating to evaluation modules, (collectively, "TI Resources") are intended to assist designers who are developing applications that incorporate TI products; by downloading, accessing or using TI Resources in any way, Designer (individually or, if Designer is acting on behalf of a company, Designer's company) agrees to use any particular TI Resource solely for this purpose and subject to the terms of this Notice.

TI's provision of TI Resources does not expand or otherwise alter TI's applicable published warranties or warranty disclaimers for TI products, and no additional obligations or liabilities arise from TI providing such TI Resources. TI reserves the right to make corrections, enhancements, improvements and other changes to its TI Resources. TI has not conducted any testing other than that specifically described in the published documentation for a particular TI Resource.

Designer is authorized to use, copy and modify any individual TI Resource only in connection with the development of applications that include the TI product(s) identified in such TI Resource. NO OTHER LICENSE, EXPRESS OR IMPLIED, BY ESTOPPEL OR OTHERWISE TO ANY OTHER TI INTELLECTUAL PROPERTY RIGHT, AND NO LICENSE TO ANY TECHNOLOGY OR INTELLECTUAL PROPERTY RIGHT OF TI OR ANY THIRD PARTY IS GRANTED HEREIN, including but not limited to any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI products or services are used. Information regarding or referencing third-party products or services does not constitute a license to use such products or services, or a warranty or endorsement thereof. Use of TI Resources may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

TI RESOURCES ARE PROVIDED "AS IS" AND WITH ALL FAULTS. TI DISCLAIMS ALL OTHER WARRANTIES OR REPRESENTATIONS, EXPRESS OR IMPLIED, REGARDING RESOURCES OR USE THEREOF, INCLUDING BUT NOT LIMITED TO ACCURACY OR COMPLETENESS, TITLE, ANY EPIDEMIC FAILURE WARRANTY AND ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE, AND NON-INFRINGEMENT OF ANY THIRD PARTY INTELLECTUAL PROPERTY RIGHTS. TI SHALL NOT BE LIABLE FOR AND SHALL NOT DEFEND OR INDEMNIFY DESIGNER AGAINST ANY CLAIM, INCLUDING BUT NOT LIMITED TO ANY INFRINGEMENT CLAIM THAT RELATES TO OR IS BASED ON ANY COMBINATION OF PRODUCTS EVEN IF DESCRIBED IN TI RESOURCES OR OTHERWISE. IN NO EVENT SHALL TI BE LIABLE FOR ANY ACTUAL, DIRECT, SPECIAL, COLLATERAL, INDIRECT, PUNITIVE, INCIDENTAL, CONSEQUENTIAL OR EXEMPLARY DAMAGES IN CONNECTION WITH OR ARISING OUT OF TI RESOURCES OR USE THEREOF, AND REGARDLESS OF WHETHER TI HAS BEEN ADVISED OF THE POSSIBILITY OF SUCH DAMAGES.

Unless TI has explicitly designated an individual product as meeting the requirements of a particular industry standard (e.g., ISO/TS 16949 and ISO 26262), TI is not responsible for any failure to meet such industry standard requirements.

Where TI specifically promotes products as facilitating functional safety or as compliant with industry functional safety standards, such products are intended to help enable customers to design and create their own applications that meet applicable functional safety standards and requirements. Using products in an application does not by itself establish any safety features in the application. Designers must ensure compliance with safety-related requirements and standards applicable to their applications. Designer may not use any TI products in life-critical medical equipment unless authorized officers of the parties have executed a special contract specifically governing such use. Life-critical medical equipment is medical equipment where failure of such equipment would cause serious bodily injury or death (e.g., life support, pacemakers, defibrillators, heart pumps, neurostimulators, and implantables). Such equipment includes, without limitation, all medical devices identified by the U.S. Food and Drug Administration as Class III devices and equivalent classifications outside the U.S.

TI may expressly designate certain products as completing a particular qualification (e.g., Q100, Military Grade, or Enhanced Product). Designers agree that it has the necessary expertise to select the product with the appropriate qualification designation for their applications and that proper product selection is at Designers' own risk. Designers are solely responsible for compliance with all legal and regulatory requirements in connection with such selection.

Designer will fully indemnify TI and its representatives against any damages, costs, losses, and/or liabilities arising out of Designer's noncompliance with the terms and provisions of this Notice.

> Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2017, Texas Instruments Incorporated